At-Speed Test and Diagnosis of Small Delay Defects

in Advanced Nanometer Technologies

1. Simulation of Small Delay Defects (Eric Schneider)

2. Test Pattern Generation Methods for Small Delay Defects (Atefe Dalirsani)

3. Robust and Hazard-Free Test Generation for Small Delay Defects (Atefe Dalirsani)

4. Nearly Robust Test Generation (Atefe Dalirsani)

5. Modeling of Delay Faults (Atefe Dalirsani)
6. **Deterministic Diagnosis of Small Delay Defects (Eric Schneider)**


7. **Small Delay Defect Diagnosis based on Statistical Timing Analysis (Eric Schneider)**


8. **Faster-Than At-Speed Test (Chang Liu)**


9. **On-Chip Delay Measurement (Chang Liu)**


10. **On-Chip Clock Generation (Chang Liu)**


11. **Shift-Power Reduction in BIST (Chang Liu)**


12. **Power-Noise/IR-Drop Reduction (Eric Schneider)**